

# Connections Between Rare-event Simulation and Bayesian inference

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## About myself

- BSc in Applied Mathematics (ITAM)
- MSc in Statistics and Operational Research (Essex)
- PhD (Sheffield, 2007/Swansea)
- Postdoc (Swansea)
- Senior Lecturer. Institute for Risk and Uncertainty, School of Engineering (Liverpool, from 2018)
  - Collaborations with GE, Parker-Hannifin, Airbus, etc.
  - 3 PhD students, 1 Postdoc
  - EPSRC Fellow 2018-2021
  - Currently visiting fellow at the Alan Turing Institute.

# Outline

- 1 THE INGREDIENTS
- 2 SUBSET SIMULATION
- 3 BUS
- 4 Examples
- 5 Conclusions

## Motivation

- Three important and challenging problems in modern science:
  - ① Identifying model parameters
  - ② Rating competitive models based on measured data
  - ③ Estimating the probability of failure of a system
- By solving them we can perform structural system identification, develop high fidelity models, design robust structures, amongst many other things.
- Two questions:
  - ① Can a **link** be established between the Bayesian updating problem and the engineering reliability problem?
  - ② If so, can we develop a robust and efficient **algorithm**?

## The Bayesian Updating Problem

- Let  $\mathcal{D}$  be an experimental dataset and  $\theta$  be the parameters of model  $\mathcal{M}$ .
- Let  $\mathcal{P}(\theta|\mathcal{M})$  be the prior distribution of  $\theta$ .
- **Aim:** to find the posterior distribution of  $\theta$  given  $\mathcal{D}$  and  $\mathcal{M}$ .

$$\mathcal{P}(\theta|\mathcal{D}, \mathcal{M}) = \frac{\mathcal{P}(\mathcal{D}|\theta, \mathcal{M})\mathcal{P}(\theta|\mathcal{M})}{\mathcal{P}(\mathcal{D}|\mathcal{M})}$$

with  $\mathcal{P}(\mathcal{D}|\mathcal{M}) = \int \mathcal{P}(\mathcal{D}|\theta, \mathcal{M})\mathcal{P}(\theta|\mathcal{M})d\theta$ .

- $\mathcal{P}(\mathcal{D}|\mathcal{M})$  is immaterial in this inference problem, but it is the main quantity of interest in model class selection as it provides the evidence.

## The Engineering Reliability Problem

- Let  $\mathcal{G} : \mathbb{R}^d \rightarrow \mathbb{R}$  be a system performance function.
- Aim:** To estimate the **probability of failure**, i.e. the probability of demand exceeding the capacity of the system.
- Let  $y^*$  be a critical value such that the system fails if  $y = \mathcal{G}(x_1, \dots, x_d) > y^*$ .
- The **failure domain**  $F$  can thus be defined as:

$$F = \{x : \mathcal{G}(x) > y^*\}$$

- The engineering reliability problem can be formulated as computing the probability of failure:

$$p_F = \mathcal{P}(X \in F) = \int_F \pi(x) dx$$

## Subset Simulation

- Developed by Au and Beck (2001) to simulate rare events and estimate small probabilities of failure.
- The idea is to decompose a rare event  $F$  into a sequence of progressively less rare events as:

$$F = F_m \subset F_{m-1} \subset \dots \subset F_1$$

where  $F_1$  is a relatively frequent event.

- Given the above sequence of events, the small probability  $\mathcal{P}(F)$  of the rare event can be represented as a product of larger probabilities as:

$$\mathcal{P}(F) = \mathcal{P}(F_m) = \mathcal{P}(F_1) \cdot \mathcal{P}(F_2|F_1) \cdot \dots \cdot \mathcal{P}(F_m|F_{m-1})$$

## Subset Simulation

- Subset simulation explores the input space  $\mathcal{X}$  by generating a relatively small number of i.i.d. samples  $x_0^{(1)}, \dots, x_0^{(n)} \sim \pi(x)$  and computing the corresponding system responses  $y_0^{(1)}, \dots, y_0^{(n)}$ .

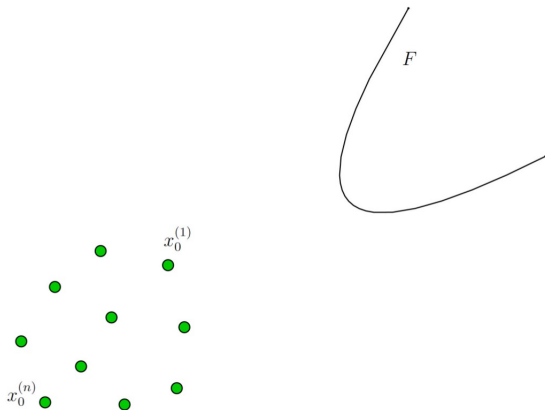


Figure taken from Zuev (2015).



## Subset Simulation

- Let  $p \in (0, 1)$  such that  $np \in \mathbb{N}$ . Define the first **intermediate failure domain** as:

$$F_1 = \left\{ x : \mathcal{G}(x) > y_1^* = \frac{y_0^{(np)} + y_0^{(np+1)}}{2} \right\}$$

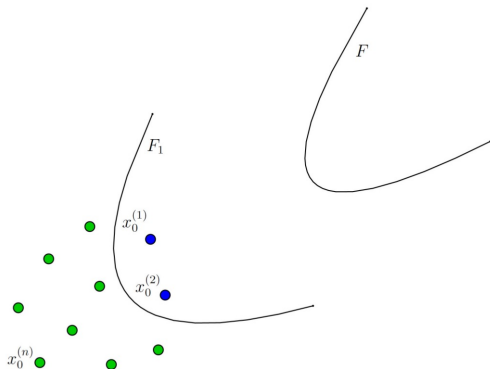


Figure taken from Zuev (2015).

## Subset Simulation

- By construction,  $x_0^{(1)}, \dots, x_0^{(np)} \in F_1$ , whilst  $x_0^{(np+1)}, \dots, x_0^{(n)} \notin F_1$ .
- Thus, the Monte Carlo estimate for the probability of  $F_1$  is given by

$$\mathcal{P}(F_1) \approx \frac{1}{n} \sum_{i=1}^n \mathcal{I}_{F_1}(x_0^{(i)}) = p$$

- $F_1$  provides a rough estimate to the failure domain  $F$ .
- Since  $F \subset F_1$ , the failure probability can be written as:

$$p_F = \mathcal{P}(F_1)\mathcal{P}(F|F_1)$$

- In the next stage, instead of sampling in the whole input space, SuS populates  $F_1$ .

## Subset Simulation

- We start with  $x_0^{(1)}, \dots, x_0^{(np)} \sim \pi(x|F_1)$  and need to draw  $n - np$  samples from  $\pi(x|F_1)$ .
- This is done with an MCMC scheme.

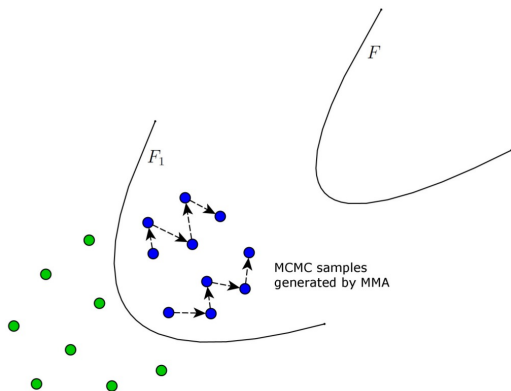


Figure taken from Zuev (2015).

## Subset Simulation

- Define the second intermediate failure domain as:

$$F_2 = \left\{ x : \mathcal{G}(x) > y_2^* = \frac{y_1^{(np)} + y_1^{(np+1)}}{2} \right\}$$

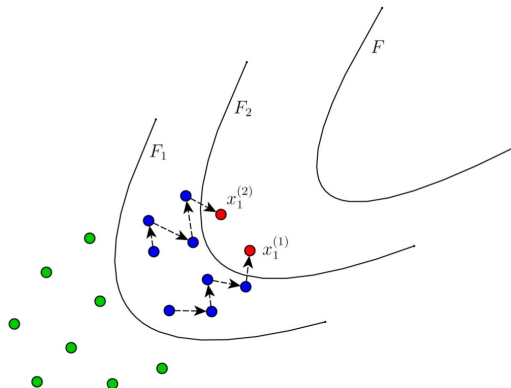


Figure taken from Zuev (2015).

## Subset Simulation

- By construction,  $x_1^{(1)}, \dots, x_1^{(np)} \in F_2$ , whilst  $x_1^{(np+1)}, \dots, x_1^{(n)} \notin F_2$ .
- Thus, the Monte Carlo estimate for the probability of  $F_2$  given  $F_1$  is equal to

$$\mathcal{P}(F_2|F_1) \approx \frac{1}{n} \sum_{i=1}^n \mathcal{I}_{F_2}(x_0^{(i)}) = p$$

- Since  $F \subset F_2 \subset F_1$ , the failure probability can be written as:

$$\begin{aligned} p_F &= \mathcal{P}(F_1)\mathcal{P}(F|F_1) \\ &= \mathcal{P}(F_1)\mathcal{P}(F_2|F_1)\mathcal{P}(F|F_2) \end{aligned}$$

- In the next stage, instead of sampling in the whole input space, SuS populates  $F_2$ .

# Modified Metropolis Algorithm

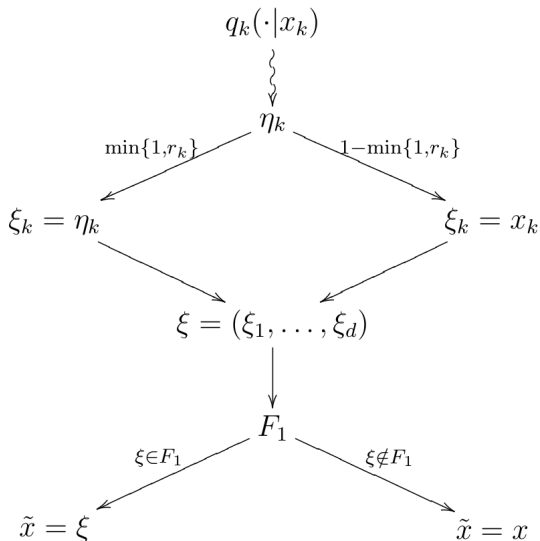


Figure taken from Zuev (2015).

## Stopping Criterion

- The number of failure samples at the  $\ell$ -th level is given by

$$n_F(\ell) = \sum_{i=1}^n \mathcal{I}_F(x_\ell^{(i)}). \text{ Observe the following:}$$

- It is likely that  $n_F(\ell) = 0$  for the first levels.
  - In general,  $n_F(\ell) \geq n_F(\ell - 1)$ .
  - $p_F = \mathcal{P}(F_1) \cdot \mathcal{P}(F_2|F_1) \cdot \dots \cdot \mathcal{P}(F_\ell|F_{\ell-1}) \cdot \mathcal{P}(F|F_\ell)$
  - $p_F \approx p^\ell \mathcal{P}(F|F_\ell)$
- The last term is estimated as  $\mathcal{P}(F|F_\ell) \approx \frac{1}{n} \sum_{i=1}^n \mathcal{I}_F(x_\ell^{(i)}) = \frac{n_F(\ell)}{n}$ .
  - If  $\frac{n_F(\ell)}{n} \geq p$ , then there are at least  $np$  failure samples. The current conditional level becomes the last level and the failure probability estimate becomes

$$p_F \approx p_F^{SuS} = p^\ell \frac{n_F(\ell)}{n}$$

- Otherwise, define the next intermediate failure domain  $F_{\ell+1}$ .

## Bayesian Updating with Structural reliability methods

- BUS (Straub and Papaioannou, 2014) connects the Bayesian updating and structural reliability problems.

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### Algorithm 1 Rejection Sampling

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**Input:** Prior distribution  $\pi(\theta)$

Likelihood  $\mathcal{L}(\theta) = \mathcal{P}(\mathcal{D}|\theta)$

$u \sim \mathcal{U}[0, 1]$

$c \in \mathbb{R}$  such that  $c\mathcal{L}(\theta) < 1$

**Output:** Posterior distribution  $\pi(\theta|\mathcal{D})$

- 1: Draw  $\theta$  from  $\pi(\theta)$ , and  $u$  from  $\mathcal{U}[0, 1]$
- 2: **if**  $u < c\mathcal{L}(\theta)$  **then**
- 3:   Accept  $\theta$
- 4: **else**
- 5:   Go to Step 1
- 6: **end if**



## Proof

- $\theta \sim \pi(\theta)$ ,  $u \sim \mathcal{U}[0, 1] = \mathcal{I}(0 \leq u \leq 1)$
- The joint pdf of  $\theta$  and  $u$  is  $\pi(\theta)\mathcal{I}(0 \leq u \leq 1)$
- The algorithm only accepts if  $u < c\mathcal{L}(\theta)$ , and produces

$$\begin{aligned} p(u, \theta) &= \frac{\pi(\theta)\mathcal{I}(0 \leq u \leq 1)\mathcal{I}(u < c\mathcal{L}(\theta))}{\int \int \pi(\theta)\mathcal{I}(0 \leq u \leq 1)\mathcal{I}(u < c\mathcal{L}(\theta))du d\theta} \\ &= \mathcal{P}_F^{-1} \pi(\theta)\mathcal{I}(0 \leq u \leq 1)\mathcal{I}(u < c\mathcal{L}(\theta)) \end{aligned}$$

- Thus, the marginal of  $\theta$  is

$$\begin{aligned} p(\theta) &= \int_0^1 p(u, \theta) du \\ &= \mathcal{P}_F^{-1} \pi(\theta) \int_0^1 \mathcal{I}(0 \leq u \leq 1)\mathcal{I}(u < c\mathcal{L}(\theta)) du \\ &= \mathcal{P}_F^{-1} \pi(\theta) c\mathcal{L}(\theta) \propto \pi(\theta|\mathcal{D}) \end{aligned}$$

## BUS

- The acceptance rate is generally low  $\Rightarrow$  use subset simulation!
- The 'failure event' is

$$\begin{aligned} F &= \{u < c\mathcal{L}(\theta)\} \\ &= \{c\mathcal{L}(\theta) - u > 0\} \\ &= \{Y > 0\} \end{aligned}$$

- **Problem 1:** It is not trivial to find an optimal  $c$ .
- **Problem 2:**  $c$  must be chosen from the beginning.

## Modified BUS

- Instead of

$$F = \{u < c\mathcal{L}(\theta)\}$$

we could redefine

$$\begin{aligned} F &= \left\{ \frac{\mathcal{L}(\theta)}{u} > \frac{1}{c} \right\} \\ &= \left\{ Y > \frac{1}{c} \right\} \end{aligned}$$

- However,  $Y = \frac{\mathcal{L}(\theta)}{u}$  is not a good choice since

$$\mathbb{E}[Y] = \mathbb{E}[\mathcal{L}(\theta)]\mathbb{E}[u^{-1}]$$

with  $\mathbb{E}[u^{-1}] = \int_0^1 u^{-1} du = \ln u|_0^1$ .

## Modified BUS

- **Proposal** (DiazDelaO et al., 2017): Define

$$\begin{aligned} F &= \left\{ \ln \left[ \frac{\mathcal{L}(\theta)}{u} \right] > -\ln c \right\} \\ &= \{Y > b\} \end{aligned}$$

### Theorem

Let  $\theta \in \mathbb{R}^n$  and  $u \in \mathbb{R}$  be independent random variables such that  $\theta \sim \pi(\theta)$  and  $u \sim U[0, 1]$ . Let  $\mathcal{L}(\theta)$  be a likelihood function and  $\mathcal{D}$  a data set. Let  $Y \equiv \ln \left[ \frac{\mathcal{L}(\theta)}{u} \right]$ . Thus, for all  $b > b_{\min} \in \mathbb{R}$ :

- 1  $p(\theta|Y > b) = \pi(\theta|\mathcal{D})$
- 2  $\mathcal{P}(\mathcal{D}) \equiv \mathcal{P}_D = e^b \mathcal{P}(Y > b)$

## Proof

$$\textcircled{1} \quad p(\theta | Y > b) = \pi(\theta | \mathcal{D})$$

The proof is analogous to the previous rejection proof since

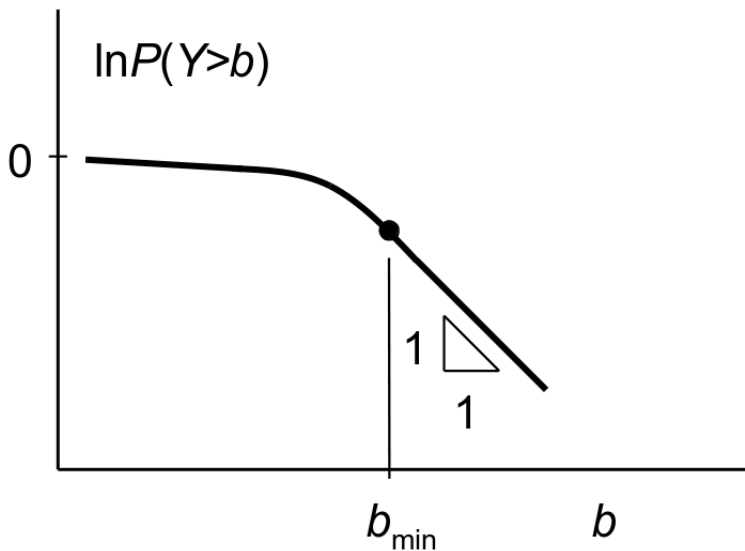
$$\mathcal{I}(Y > b) = \mathcal{I}(u < c\mathcal{L}(\theta))$$

$$\textcircled{2} \quad \mathcal{P}(\mathcal{D}) \equiv \mathcal{P}_D = e^b \mathcal{P}(Y > b)$$

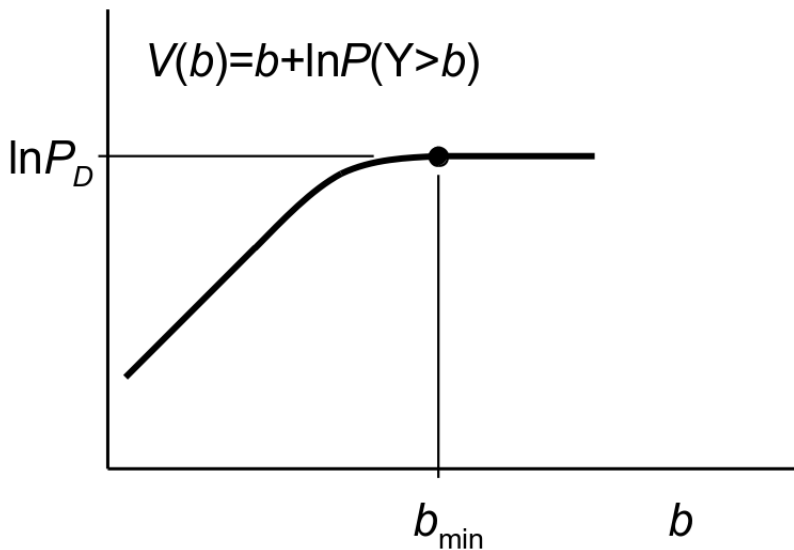
To prove this, note that

$$\begin{aligned} \mathcal{P}(Y > b) &= \int \int \pi(\theta) \mathcal{I}(0 \leq u \leq 1) \mathcal{I}(\ln \left[ \frac{\mathcal{L}(\theta)}{u} \right] > b) du d\theta \\ &= \int \pi(\theta) \int_0^1 \mathcal{I}(u < e^{-b} \mathcal{L}(\theta)) du d\theta \\ &= e^{-b} \int \pi(\theta) \mathcal{L}(\theta) d\theta = e^{-b} \mathcal{P}_D \end{aligned}$$

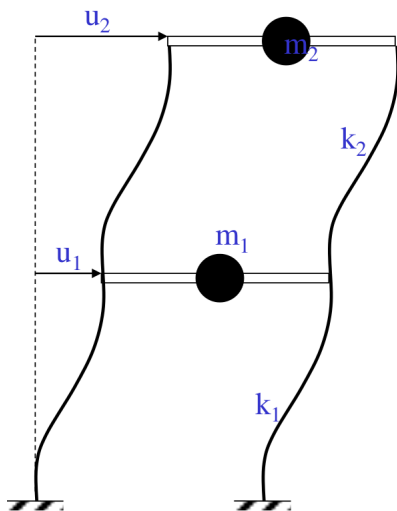
## Characteristic Trends



## Characteristic Trends



## Example



- Consider the following two DOF shear building model.
- The stiffnesses are given by  $\theta_1 \bar{k}_1$  and  $\theta_2 \bar{k}_2$  for  $\bar{k}_i = 29.7 \times 10^6$  N/m.
- The joint prior distribution for  $\theta_1$  and  $\theta_2$  is assumed to be the product of two lognormals with modes 1.3 and 0.8 and unit standard deviation.
- Our goal is to identify  $\theta_1$  and  $\theta_2$  given modal data.



## Example

- The likelihood is given by

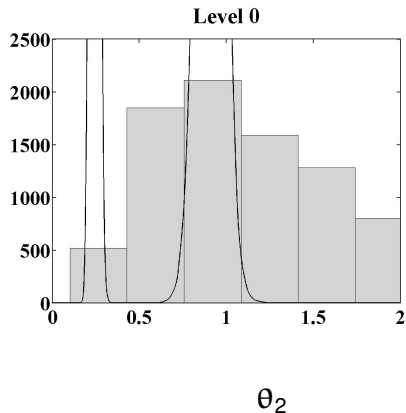
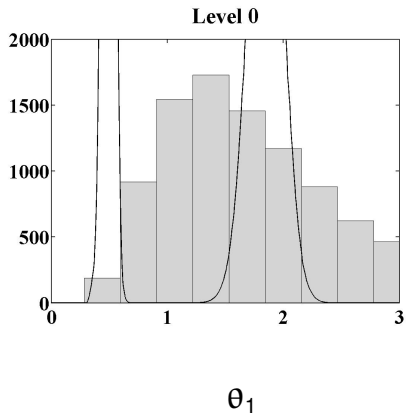
$$\mathcal{L}(\boldsymbol{\theta}) \propto \exp \left\{ -\frac{J(\boldsymbol{\theta})}{2\sigma_\epsilon^2} \right\}$$

where

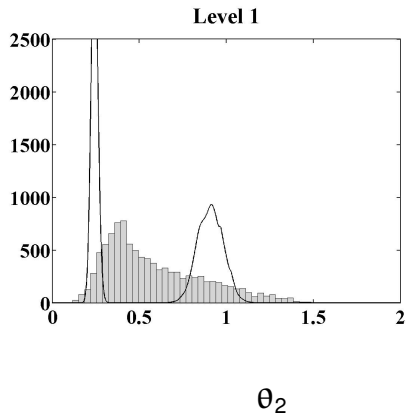
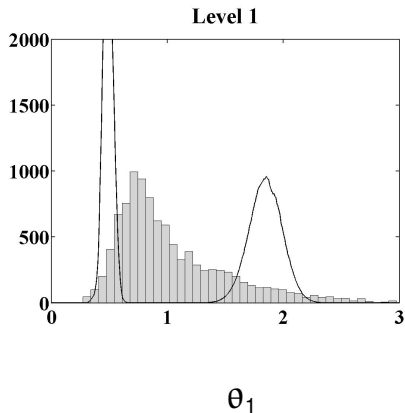
$$J(\boldsymbol{\theta}) = \sum_{j=1}^2 \lambda_j^2 \left[ \frac{f_j^2}{\tilde{f}_j^2} - 1 \right]^2$$

- $\mathcal{D} = \{ \tilde{f}_1, \tilde{f}_2 \} = \{ 3.13, 9.83 \} \text{ Hz}$
- $f_1$  y  $f_2$  are natural frequencies obtained through finite element modelling.

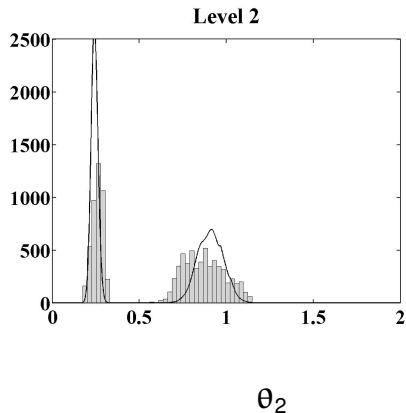
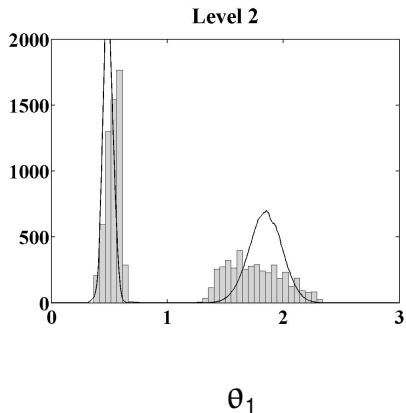
# Marginal Distributions



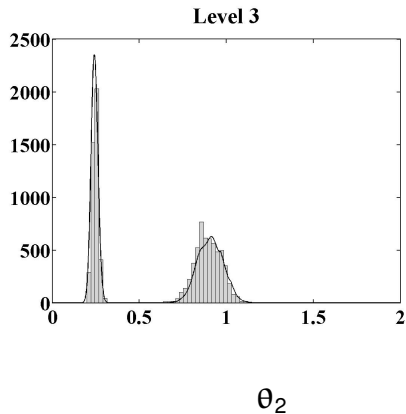
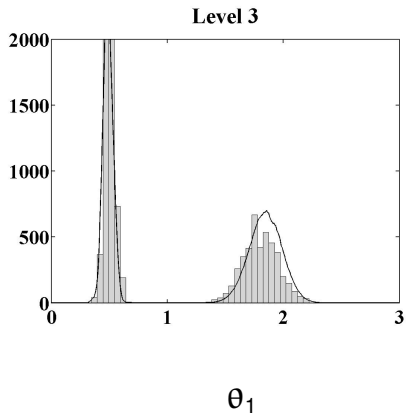
# Marginal Distributions



# Marginal Distributions

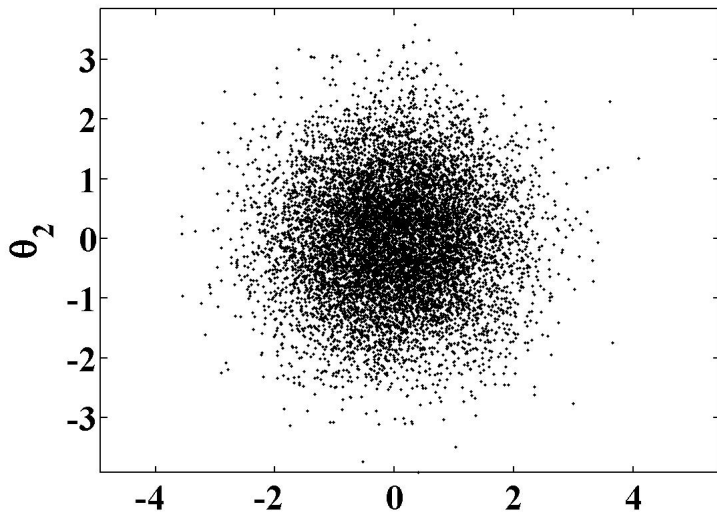


# Marginal Distributions

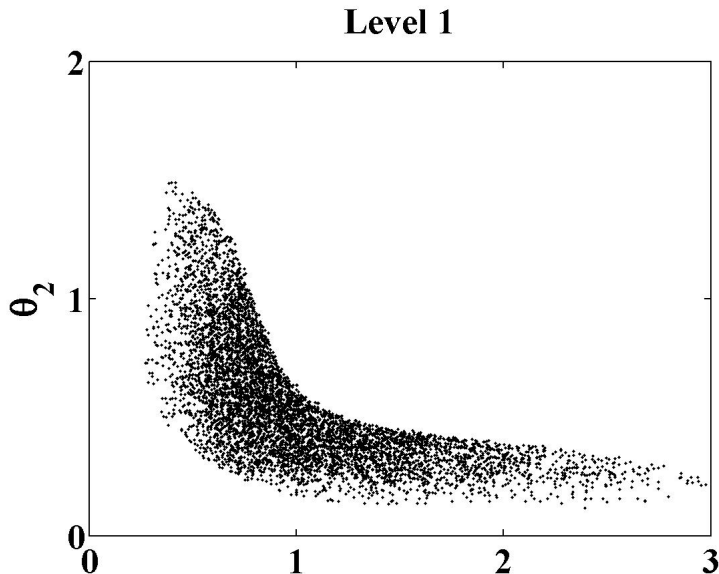


# Parameter Space

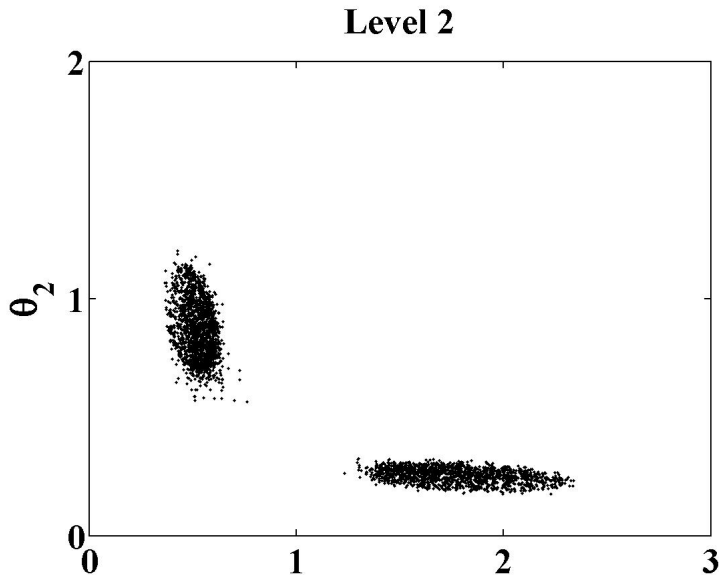
## Level 0



# Parameter Space

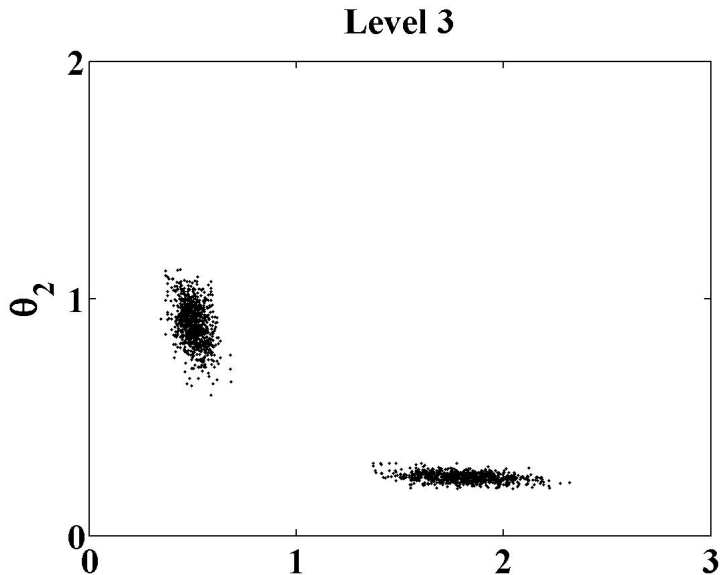


# Parameter Space

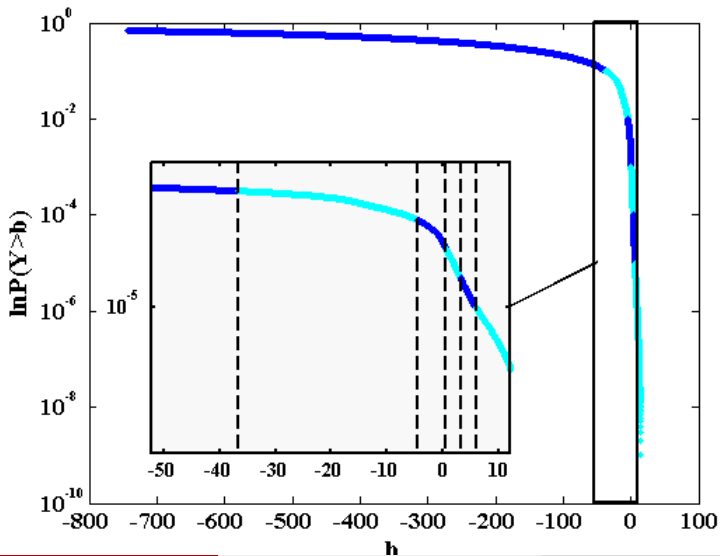




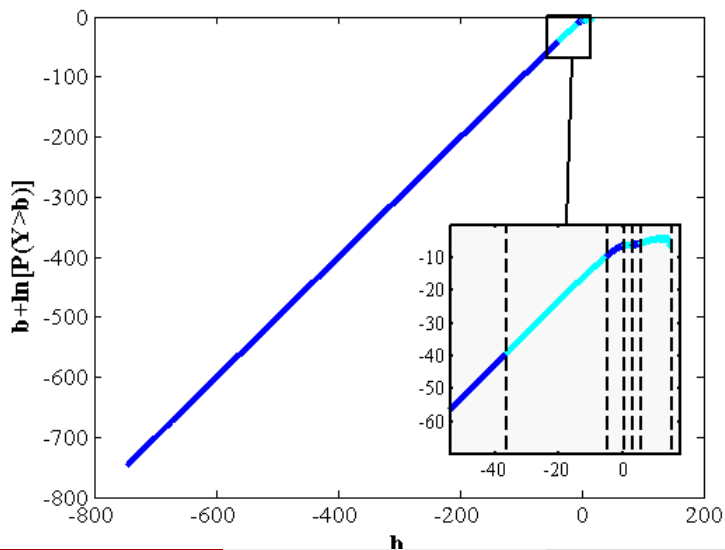
# Parameter Space



## MBUS



## MBUS



## Automatic Stopping Criterion

- We know that

$$P_{F_k} = e^{-b_k} P_D$$

- Let  $B_k = \{\theta : \mathcal{L}(\theta) > e^{b_k}\}$  be an inadmissible set. We can prove that

$$P_{F_k} = P_{\theta}\{B_k\} + e^{-b_k} P_D P_{\theta|D}\{B_k^c\}$$

- Moreover, we can prove that

$$\emptyset \subset \dots \subset B_{k+1} \subset B_k,$$

- By defining  $a_k = P_{\theta}\{B_k\}$  we have a monotone decreasing sequence of values such that  $a_k \searrow 0$ .
- Therefore, we can stop the algorithm for a small enough value of  $a_k$  which can be determined with an “outer” SuS run.

## GPE Hyper-parameters

- Build the surrogate with data from training runs

$$\mathcal{D} = \{(y_1, \vec{x}_1), \dots, (y_n, \vec{x}_n)\}.$$

- Assumed structure on the output

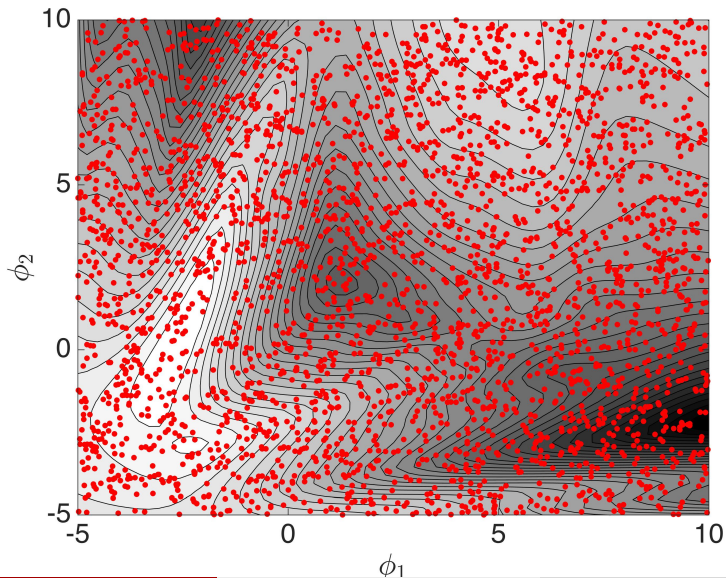
$$\eta(\vec{x}) = \underbrace{h(\vec{x})^T \beta}_{\text{Global trend}} + \underbrace{Z(\vec{x}|\sigma^2, \phi)}_{\text{Local variations}}$$

- Covariance function (kernel)

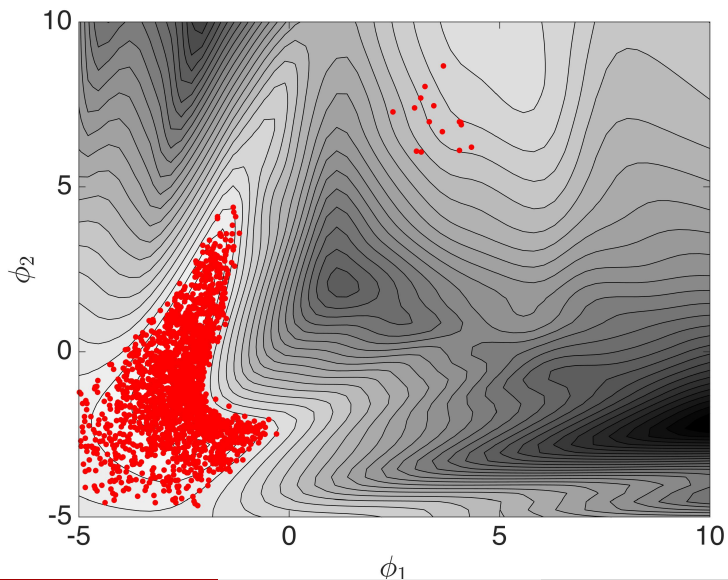
$$k(\vec{x}, \vec{x}'|\phi) = \sigma^2 \exp \left\{ -\frac{1}{2} \sum_{i=1}^p \frac{(x_i - x'_i)^2}{\phi_i} \right\}.$$

- Hyper-parameters:  $\theta = \{\beta, \sigma^2, \phi\}$

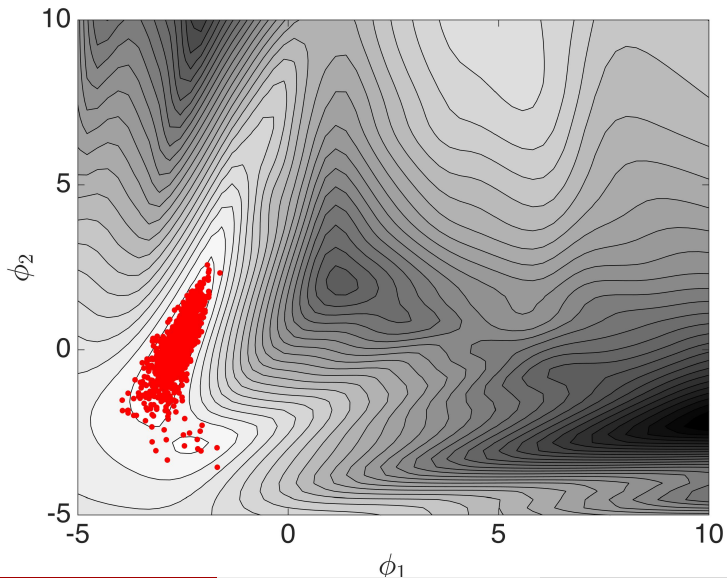
# GPE Hyper-parameters



# GPE Hyper-parameters



## GPE Hyper-parameters





## Summary

- BUS (Straub and Papaioannou, 2014) bridges the gap between the reliability problem and the Bayesian inference problem.
- As it is formulated, BUS requires the choice of a multiplier that, chosen incorrectly, the performance of the algorithm is affected.
- DiazDelaO et al. (2017) redefine the failure event, expressing the driving variable without the need of the multiplier.
- The implementation no longer requires a predetermined value of the multiplier, thus eliminating the need to rerun the algorithm in case an inadmissible or inefficient value is chosen.
- Different stopping criteria can be implemented.

## References

- 1 Au, S.K. and Beck, J. (2001) Estimation of small failure probabilities in high dimensions by subset simulation, *Probabilistic Engineering Mechanics*, 16 (4), 263-277.
- 2 Straub, D. and Papaioannou, I. (2014) Bayesian updating with structural reliability methods, *Journal of Engineering Mechanics*.
- 3 DiazDelaO, F.A., Garbuno-Inigo, A., Au. S.K., Yoshida, I. (2017) Bayesian updating and model class selection with subset simulation, *CMAME*.
- 4 Zuev, K.M. (2015) Subset Simulation Method for Rare Event Estimation: An Introduction, *Encyclopedia of Earthquake Engineering*.

# Thank you!